

Anna Lee N. Tinio

From: 박승호 [almpark@samsung.com]
Sent: Thursday, August 17, 2006 6:04 AM
To: Anna Lee N. Tinio
Cc: 박승호; PCTEST - Gregory Czumak
Subject: Re: Additional Info

Hello Anna Lee

1. We have received your response to our questions regarding the referenced application - thank you. However, in response to the second question asking for the Bluetooth dwell time plot, in the modified Bluetooth test report that you submitted. the last page now contains an output power plot, identical to the one already on page 20 of that report. Please submit the dwell time plot for the EUT.

-> When we test the BT Power and BT Dwell time , we are using the spectrum analyzer's function.

The function can measure BT Output Power and Dwell time simultaneously.

You can see the **Output Power** and **Full Burst Width** at Plot.

I Hope you consider it once more .

If it possible the BT report ,which was submitted at first may be useful.

Sincerely

SEOUNG HO PARK

----- **Original Message** -----

Sender : Anna Lee N. Tinio<annalee@pctestlab.com>

Date : 2006-08-17 05:19

Title : Additional Info

To: Mr. Seoung-Ho Park / Samsung Electronics Co., Ltd.

From: Mr. Gregory Czumak / PCTEST TCB

RE: FCC ID: A3LSGHZ620

Applicant: Samsung Electronics Co., Ltd.

Correspondence Reference Number: A3L0458-1

Confirmation Number: 1608040458

Date of Original Email: August 16, 2006

Subject: Request for additional information<?xml:namespace prefix = o ns = "urn:schemas-microsoft-com:office:office" />

In regards to your recent TCB application referenced above, we kindly request that you provide the following additional information.

1. We have received your response to our questions regarding the referenced application - thank you. However, in response to the second question asking for the Bluetooth dwell time plot, in the modified Bluetooth test report that you submitted. the last page now contains an output power plot, identical to the one already on page 20 of that report. Please submit the dwell time plot for the EUT.

The items indicated above must be submitted before processing can continue on the above referenced application.

Sincerely,

8/17/2006

Gregory Czumak
Quality Manager
Senior Certification Engineer

PCTEST Engineering Laboratory, Inc.

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SEOUNG HO PARK

Senior Manager

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